


<b>Issue Classification</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/006,669	OGAWA ET AL.	
	Examiner	Art Unit	
	Gabriel L. Chu	2114	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
714	8			714	710				
INTERNATIONAL CLASSIFICATION									
G06F	11/00								
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	/								
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<i>reilly</i> (Assistant Examiner)	<i>5/26/05</i> (Date)	<i>Robert W. Beausoliel</i> <b>ROBERT BEAUSOLIEL</b> <b>SUPERVISORY PATENT EXAMINER</b> <b>TECHNOLOGY CENTER 2100</b> (Primary Examiner)	Total Claims Allowed: <i>5</i>
<i>Delella</i> (Legal Instruments Examiner)	<i>6/2/05</i> (Date)		O.G. Print Claim(s) <i>1</i>

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA			<input type="checkbox"/> T.D.			<input type="checkbox"/> R.1.47	
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